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PATENT

## In the United States Patent and Trademark Office

Applicants: Linda BRALY et al. )  
Applicants' Reference: LAM2P298 ) Examiner: Unassigned  
Application No. 10/002,676 ) Group Art Unit: 1765  
Filed: October 31, 2001 ) Date: February 20, 2003  
Title: METHOD FOR PLANARIZATION ETCH )  
WITH IN-SITU MONITORING BY )  
INTERFEROMETRY PRIOR TO RECESS ETCH )

### CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, Washington, DC 20231 on February 20, 2003.

Signed:   
Diane Schwanbeck

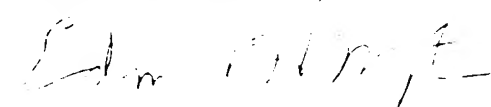
## Separate Letter to the Official Draftsperson

Commissioner for Patents  
Box: Official Draftsperson  
Washington, D.C. 20231

Dear Sir:

Applicants hereby attach thirteen (13) sheets of formal drawings (Figures 1-13) for the above-referenced patent application. In the event the Draftsperson has any questions concerning the formal drawings, he or she is respectfully requested to contact the undersigned. If any fees are due in connection with the filing of these drawings, then please charge such fees to our Deposit Account No. 50-0805 (Order No. LAM2P298).

Respectfully submitted,  
MARTINE & PENILLA, LLP

  
Edmund H. Mizumoto, Esq.  
Reg. No. 46,938

710 Lakeway Drive, Suite 170  
Sunnyvale, California 94085  
(408) 749-6900  
Customer No. 25920

Attorney Docket No. LAM2P298